

Notice of References Cited

Application/Control No.

10/536,716

Applicant(s)/Patent Under

Reexamination

VERFAILLIE ET AL.

Examiner

CELINE X. QIAN

Art Unit

1636

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U.S. PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
A	US-			
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FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
U	Hatada et al (PNAS, December 2000. Vol.97, No.25, pages 13807-13811)
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